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**Understanding Embedded - CPLDs (Complex Programmable Logic Devices)** 

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

## **Applications of Embedded - CPLDs**

Details	
Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	7.5 ns
Voltage Supply - Internal	3V ~ 3.6V
Number of Logic Elements/Blocks	2
Number of Macrocells	32
Number of Gates	600
Number of I/O	36
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	44-LCC (J-Lead)
Supplier Device Package	44-PLCC (16.59x16.59)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epm7032aelc44-7

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Table 1. MAX 700	Table 1. MAX 7000A Device Features											
Feature	EPM7032AE	EPM7064AE	EPM7128AE	EPM7256AE	EPM7512AE							
Usable gates	600	1,250	2,500	5,000	10,000							
Macrocells	32	64	128	256	512							
Logic array blocks	2	4	8	16	32							
Maximum user I/O pins	36	68	100	164	212							
t <sub>PD</sub> (ns)	4.5	4.5	5.0	5.5	7.5							
t <sub>SU</sub> (ns)	2.9	2.8	3.3	3.9	5.6							
t <sub>FSU</sub> (ns)	2.5	2.5	2.5	2.5	3.0							
t <sub>CO1</sub> (ns)	3.0	3.1	3.4	3.5	4.7							
f <sub>CNT</sub> (MHz)	227.3	222.2	192.3	172.4	116.3							

## ...and More Features

- 4.5-ns pin-to-pin logic delays with counter frequencies of up to 227.3 MHz
- MultiVolt<sup>TM</sup> I/O interface enables device core to run at 3.3 V, while I/O pins are compatible with 5.0-V, 3.3-V, and 2.5-V logic levels
- Pin counts ranging from 44 to 256 in a variety of thin quad flat pack (TQFP), plastic quad flat pack (PQFP), ball-grid array (BGA), spacesaving FineLine BGA™, and plastic J-lead chip carrier (PLCC) packages
- Supports hot-socketing in MAX 7000AE devices
- Programmable interconnect array (PIA) continuous routing structure for fast, predictable performance
- PCI-compatible
- Bus-friendly architecture, including programmable slew-rate control
- Open-drain output option
- Programmable macrocell registers with individual clear, preset, clock, and clock enable controls
- Programmable power-up states for macrocell registers in MAX 7000AE devices
- Programmable power-saving mode for 50% or greater power reduction in each macrocell
- Configurable expander product-term distribution, allowing up to 32 product terms per macrocell
- Programmable security bit for protection of proprietary designs
- 6 to 10 pin- or logic-driven output enable signals
- Two global clock signals with optional inversion
- Enhanced interconnect resources for improved routability
- Fast input setup times provided by a dedicated path from I/O pin to macrocell registers
- Programmable output slew-rate control
- Programmable ground pins

- Software design support and automatic place-and-route provided by Altera's development systems for Windows-based PCs and Sun SPARCstation, and HP 9000 Series 700/800 workstations
- Additional design entry and simulation support provided by EDIF 2 0 0 and 3 0 0 netlist files, library of parameterized modules (LPM), Verilog HDL, VHDL, and other interfaces to popular EDA tools from manufacturers such as Cadence, Exemplar Logic, Mentor Graphics, OrCAD, Synopsys, Synplicity, and VeriBest
- Programming support with Altera's Master Programming Unit (MPU), MasterBlaster™ serial/universal serial bus (USB) communications cable, ByteBlasterMV™ parallel port download cable, and BitBlaster™ serial download cable, as well as programming hardware from third-party manufacturers and any Jam™ STAPL File (.jam), Jam Byte-Code File (.jbc), or Serial Vector Format File- (.svf) capable in-circuit tester

# General Description

MAX 7000A (including MAX 7000AE) devices are high-density, high-performance devices based on Altera's second-generation MAX architecture. Fabricated with advanced CMOS technology, the EEPROM-based MAX 7000A devices operate with a 3.3-V supply voltage and provide 600 to 10,000 usable gates, ISP, pin-to-pin delays as fast as 4.5 ns, and counter speeds of up to 227.3 MHz. MAX 7000A devices in the -4, -5, -6, -7, and some -10 speed grades are compatible with the timing requirements for 33 MHz operation of the PCI Special Interest Group (PCI SIG) *PCI Local Bus Specification, Revision 2.2.* See Table 2.

Device	Speed Grade							
	-4	-5	-6	-7	-10	-12		
EPM7032AE	<b>✓</b>			<b>✓</b>	<b>✓</b>			
EPM7064AE	<b>✓</b>			<b>✓</b>	<b>✓</b>			
EPM7128A			<b>✓</b>	<b>✓</b>	✓	<b>✓</b>		
EPM7128AE		<b>✓</b>		<b>✓</b>	✓			
EPM7256A			<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>		
EPM7256AE		<b>✓</b>		<b>✓</b>	✓			
EPM7512AE				<b>✓</b>	<b>✓</b>	<b>✓</b>		

The MAX 7000A architecture supports 100% transistor-to-transistor logic (TTL) emulation and high-density integration of SSI, MSI, and LSI logic functions. It easily integrates multiple devices including PALs, GALs, and 22V10s devices. MAX 7000A devices are available in a wide range of packages, including PLCC, BGA, FineLine BGA, Ultra FineLine BGA, PQFP, and TQFP packages. See Table 3 and Table 4.

Table 3. MAX 70	100A Maximum L	lser I/O Pins	Note (1)			
Device	44-Pin PLCC	44-Pin TQFP	49-Pin Ultra FineLine BGA (2)	84-Pin PLCC	100-Pin TQFP	100-Pin FineLine BGA (3)
EPM7032AE	36	36				
EPM7064AE	36	36	41		68	68
EPM7128A				68	84	84
EPM7128AE				68	84	84
EPM7256A					84	
EPM7256AE					84	84
EPM7512AE						

Table 4. MAX 7000.	Table 4. MAX 7000A Maximum User I/O Pins Note (1)										
Device	144-Pin TQFP	169-Pin Ultra FineLine BGA (2)	208-Pin PQFP	256-Pin BGA	256-Pin FineLine BGA (3)						
EPM7032AE											
EPM7064AE											
EPM7128A	100				100						
EPM7128AE	100	100			100						
EPM7256A	120		164		164						
EPM7256AE	120		164		164						
EPM7512AE	120		176	212	212						

#### Notes to tables:

- When the IEEE Std. 1149.1 (JTAG) interface is used for in-system programming or boundary-scan testing, four I/O pins become JTAG pins.
- (2) All Ultra FineLine BGA packages are footprint-compatible via the SameFrame<sup>TM</sup> feature. Therefore, designers can design a board to support a variety of devices, providing a flexible migration path across densities and pin counts. Device migration is fully supported by Altera development tools. See "SameFrame Pin-Outs" on page 15 for more details.
- (3) All FineLine BGA packages are footprint-compatible via the SameFrame feature. Therefore, designers can design a board to support a variety of devices, providing a flexible migration path across densities and pin counts. Device migration is fully supported by Altera development tools. See "SameFrame Pin-Outs" on page 15 for more details.

## **Expander Product Terms**

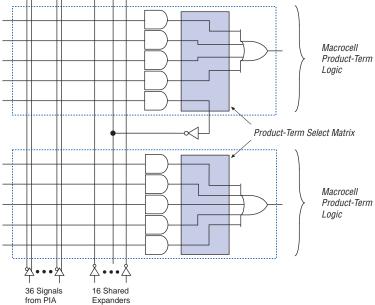
Although most logic functions can be implemented with the five product terms available in each macrocell, more complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources. However, the MAX 7000A architecture also offers both shareable and parallel expander product terms that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

## Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay ( $t_{SEXP}$ ) is incurred when shareable expanders are used. Figure 3 shows how shareable expanders can feed multiple macrocells.

Shareable expanders can be shared by any or all macrocells in an LAB.

Figure 3. MAX 7000A Shareable Expanders





For more information on using the Jam STAPL language, see *Application Note 88* (Using the Jam Language for ISP & ICR via an Embedded Processor) and *Application Note 122* (Using Jam STAPL for ISP & ICR via an Embedded Processor).

ISP circuitry in MAX 7000AE devices is compliant with the IEEE Std. 1532 specification. The IEEE Std. 1532 is a standard developed to allow concurrent ISP between multiple PLD vendors.

## **Programming Sequence**

During in-system programming, instructions, addresses, and data are shifted into the MAX 7000A device through the TDI input pin. Data is shifted out through the TDO output pin and compared against the expected data.

Programming a pattern into the device requires the following six ISP stages. A stand-alone verification of a programmed pattern involves only stages 1, 2, 5, and 6.

- Enter ISP. The enter ISP stage ensures that the I/O pins transition smoothly from user mode to ISP mode. The enter ISP stage requires 1 ms.
- 2. *Check ID*. Before any program or verify process, the silicon ID is checked. The time required to read this silicon ID is relatively small compared to the overall programming time.
- 3. *Bulk Erase*. Erasing the device in-system involves shifting in the instructions to erase the device and applying one erase pulse of 100 ms.
- Program. Programming the device in-system involves shifting in the address and data and then applying the programming pulse to program the EEPROM cells. This process is repeated for each EEPROM address.
- Verify. Verifying an Altera device in-system involves shifting in addresses, applying the read pulse to verify the EEPROM cells, and shifting out the data for comparison. This process is repeated for each EEPROM address.
- 6. Exit ISP. An exit ISP stage ensures that the I/O pins transition smoothly from ISP mode to user mode. The exit ISP stage requires 1 ms.

Table 8. MAX 7000A	JTAG Instructions
JTAG Instruction	Description
SAMPLE/PRELOAD	Allows a snapshot of signals at the device pins to be captured and examined during normal device operation, and permits an initial data pattern output at the device pins
EXTEST	Allows the external circuitry and board-level interconnections to be tested by forcing a test pattern at the output pins and capturing test results at the input pins
BYPASS	Places the 1-bit bypass register between the TDI and TDO pins, which allows the BST data to pass synchronously through a selected device to adjacent devices during normal device operation
IDCODE	Selects the IDCODE register and places it between the TDI and TDO pins, allowing the IDCODE to be serially shifted out of TDO
USERCODE	Selects the 32-bit USERCODE register and places it between the TDI and TDO pins, allowing the USERCODE value to be shifted out of TDO. The USERCODE instruction is available for MAX 7000AE devices only
UESCODE	These instructions select the user electronic signature (UESCODE) and allow the UESCODE to be shifted out of TDO. UESCODE instructions are available for EPM7128A and EPM7256A devices only.
ISP Instructions	These instructions are used when programming MAX 7000A devices via the JTAG ports with the MasterBlaster, ByteBlasterMV, or BitBlaster download cable, or using a Jam STAPL File, JBC File, or SVF File via an embedded processor or test equipment.

## Programmable Speed/Power Control

MAX 7000A devices offer a power-saving mode that supports low-power operation across user-defined signal paths or the entire device. This feature allows total power dissipation to be reduced by 50% or more because most logic applications require only a small fraction of all gates to operate at maximum frequency.

The designer can program each individual macrocell in a MAX 7000A device for either high-speed (i.e., with the Turbo Bit<sup>TM</sup> option turned on) or low-power operation (i.e., with the Turbo Bit option turned off). As a result, speed-critical paths in the design can run at high speed, while the remaining paths can operate at reduced power. Macrocells that run at low power incur a nominal timing delay adder ( $t_{LPA}$ ) for the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{EN}$ ,  $t_{SEXP}$ ,  $t_{ACL}$ , and  $t_{CPPW}$  parameters.

## Output Configuration

MAX 7000A device outputs can be programmed to meet a variety of system-level requirements.

## MultiVolt I/O Interface

The MAX 7000A device architecture supports the MultiVolt I/O interface feature, which allows MAX 7000A devices to connect to systems with differing supply voltages. MAX 7000A devices in all packages can be set for 2.5-V, 3.3-V, or 5.0-V I/O pin operation. These devices have one set of VCC pins for internal operation and input buffers (VCCINT), and another set for I/O output drivers (VCCIO).

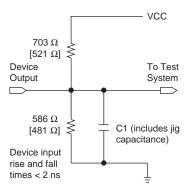
The VCCIO pins can be connected to either a 3.3-V or 2.5-V power supply, depending on the output requirements. When the VCCIO pins are connected to a 2.5-V power supply, the output levels are compatible with 2.5-V systems. When the VCCIO pins are connected to a 3.3-V power supply, the output high is at 3.3 V and is therefore compatible with 3.3-V or 5.0-V systems. Devices operating with V<sub>CCIO</sub> levels lower than 3.0 V incur a slightly greater timing delay of  $t_{OD2}$  instead of  $t_{OD1}$ . Inputs can always be driven by 2.5-V, 3.3-V, or 5.0-V signals.

Table 12 describes the MAX 7000A MultiVolt I/O support.

Table 12. MAX 7000A MultiVolt I/O Support											
V <sub>CCIO</sub> Voltage Input Signal (V) Output Signal (V)											
	2.5 3.3 5.0 2.5 3.3 5.0										
2.5	<b>✓</b>	<b>✓</b>	<b>✓</b>	<b>✓</b>							
3.3	3.3 🗸 🗸 🗸										

## Figure 9. MAX 7000A AC Test Conditions

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast-groundcurrent transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in brackets are for 2.5-V outputs. Numbers without brackets are for 3.3-V outputs.



# Operating Conditions

Tables 13 through 16 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for MAX 7000A devices.

Table 1	Table 13. MAX 7000A Device Absolute Maximum Ratings   Note (1)										
Symbol	Parameter	Conditions	Min	Max	Unit						
V <sub>CC</sub>	Supply voltage	With respect to ground (2)	-0.5	4.6	V						
VI	DC input voltage		-2.0	5.75	V						
I <sub>OUT</sub>	DC output current, per pin		-25	25	mA						
T <sub>STG</sub>	Storage temperature	No bias	-65	150	°C						
T <sub>A</sub>	Ambient temperature	Under bias	-65	135	°C						
TJ	Junction temperature	BGA, FineLine BGA, PQFP, and TQFP packages, under bias		135	°C						

Symbol	Parameter	Conditions	Min	Max	Unit
V <sub>IH</sub>	High-level input voltage		1.7	5.75	V
V <sub>IL</sub>	Low-level input voltage		-0.5	0.8	V
V <sub>OH</sub>	3.3-V high-level TTL output voltage	$I_{OH} = -8 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V}$ (7)	2.4		V
	3.3-V high-level CMOS output voltage	$I_{OH} = -0.1 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V}$ (7)	V <sub>CCIO</sub> – 0.2		V
	2.5-V high-level output voltage	$I_{OH} = -100 \mu A DC, V_{CCIO} = 2.30 V$ (7)	2.1		V
		I <sub>OH</sub> = -1 mA DC, V <sub>CCIO</sub> = 2.30 V (7)	2.0		V
		$I_{OH} = -2 \text{ mA DC}, V_{CCIO} = 2.30 \text{ V } (7)$	1.7		V
V <sub>OL</sub>	3.3-V low-level TTL output voltage	$I_{OL} = 8 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V } (8)$		0.45	V
	3.3-V low-level CMOS output voltage	$I_{OL} = 0.1 \text{ mA DC}, V_{CCIO} = 3.00 \text{ V } (8)$		0.2	V
	2.5-V low-level output voltage	$I_{OL} = 100 \mu A DC, V_{CCIO} = 2.30 V (8)$		0.2	V
		I <sub>OL</sub> = 1 mA DC, V <sub>CCIO</sub> = 2.30 V (8)		0.4	V
		I <sub>OL</sub> = 2 mA DC, V <sub>CCIO</sub> = 2.30 V (8)		0.7	V
կ	Input leakage current	$V_I = -0.5 \text{ to } 5.5 \text{ V } (9)$	-10	10	μΑ
I <sub>OZ</sub>	Tri-state output off-state current	V <sub>I</sub> = -0.5 to 5.5 V (9)	-10	10	μΑ
R <sub>ISP</sub>	Value of I/O pin pull-up resistor	V <sub>CCIO</sub> = 3.0 to 3.6 V (10)	20	50	kΩ
	during in-system programming	V <sub>CCIO</sub> = 2.3 to 2.7 V (10)	30	80	kΩ
	or during power-up	V <sub>CCIO</sub> = 2.3 to 3.6 V (11)	20	74	kΩ

Table 1	Table 16. MAX 7000A Device Capacitance   Note (12)								
Symbol	Parameter Conditions Min Max Uni								
C <sub>IN</sub>	Input pin capacitance	V <sub>IN</sub> = 0 V, f = 1.0 MHz		8	pF				
C <sub>I/O</sub>	I/O pin capacitance	V <sub>OUT</sub> = 0 V, f = 1.0 MHz		8	pF				

#### MAX 7000A Programmable Logic Device Data Sheet

#### Notes to tables:

- (1) See the Operating Requirements for Altera Devices Data Sheet.
- (2) Minimum DC input voltage is –0.5 V. During transitions, the inputs may undershoot to –2.0 V for input currents less than 100 mA and periods shorter than 20 ns.
- (3) For EPM7128A and EPM7256A devices only, V<sub>CC</sub> must rise monotonically.
- (4) In MAX 7000AE devices, all pins, including dedicated inputs, I/O pins, and JTAG pins, may be driven before V<sub>CCINT</sub> and V<sub>CCIO</sub> are powered.
- (5) These devices support in-system programming for -40° to 100° C. For in-system programming support between -40° and 0° C, contact Altera Applications.
- (6) These values are specified under the recommended operating conditions shown in Table 14 on page 28.
- (7) The parameter is measured with 50% of the outputs each sourcing the specified current. The  $I_{OH}$  parameter refers to high-level TTL or CMOS output current.
- (8) The parameter is measured with 50% of the outputs each sinking the specified current. The I<sub>OL</sub> parameter refers to low-level TTL or CMOS output current.
- (9) This value is specified for normal device operation. For MAX 7000AE devices, the maximum leakage current during power-up is ±300 μA. For EPM7128A and EPM7256A devices, leakage current during power-up is not specified.
- (10) For EPM7128A and EPM7256A devices, this pull-up exists while a device is programmed in-system.
- (11) For MAX 7000AE devices, this pull-up exists while devices are programmed in-system and in unprogrammed devices during power-up.
- (12) Capacitance is measured at 25 °C and is sample-tested only. The OE1 pin (high-voltage pin during programming) has a maximum capacitance of 20 pF.
- (13) The POR time for MAX 7000AE devices (except MAX 7128A and MAX 7256A devices) does not exceed 100  $\mu$ s. The sufficient V<sub>CCINT</sub> voltage level for POR is 3.0 V. The device is fully initialized within the POR time after V<sub>CCINT</sub> reaches the sufficient POR voltage level.

Tables 17 through 30 show EPM7032AE, EPM7064AE, EPM7128AE, EPM7256AE, EPM7512AE, EPM7128A, and EPM7256A timing information.

Symbol	Parameter	Conditions	Speed Grade						Unit
			-,	4		7	-1	10	
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF (2)		4.5		7.5		10	ns
t <sub>SU</sub>	Global clock setup time	(2)	2.9		4.7		6.3		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.0	1.0	5.0	1.0	6.7	ns
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.6		2.5		3.6		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.3		0.5		0.5		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	4.3	1.0	7.2	1.0	9.4	ns
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	2.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		4.4		7.2		9.7	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	227.3		138.9		103.1		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		4.4		7.2		9.7	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	227.3		138.9		103.1		MHz

Symbol	Parameter	Conditions	Speed Grade						Unit
			-	-4		-7		10	
			Min	Max	Min	Max	Min	Max	
t <sub>IN</sub>	Input pad and buffer delay			0.6		1.1		1.4	ns
t <sub>IO</sub>	I/O input pad and buffer delay			0.6		1.1		1.4	ns
t <sub>FIN</sub>	Fast input delay			2.5		3.0		3.7	ns
t <sub>SEXP</sub>	Shared expander delay			1.8		3.0		3.9	ns
$t_{PEXP}$	Parallel expander delay			0.4		0.7		0.9	ns
$t_{LAD}$	Logic array delay			1.5		2.5		3.2	ns
t <sub>LAC</sub>	Logic control array delay			0.6		1.0		1.2	ns
t <sub>IOE</sub>	Internal output enable delay			0.0		0.0		0.0	ns
t <sub>OD1</sub>	Output buffer and pad delay, slow slew rate = off V <sub>CCIO</sub> = 3.3 V	C1 = 35 pF		0.8		1.3		1.8	ns
t <sub>OD2</sub>	Output buffer and pad delay, slow slew rate = off V <sub>CCIO</sub> = 2.5 V	C1 = 35 pF (5)		1.3		1.8		2.3	ns
t <sub>OD3</sub>	Output buffer and pad delay, slow slew rate = on V <sub>CCIO</sub> = 2.5 V or 3.3 V	C1 = 35 pF		5.8		6.3		6.8	ns
t <sub>ZX1</sub>	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 3.3 \text{ V}$	C1 = 35 pF		4.0		4.0		5.0	ns
t <sub>ZX2</sub>	Output buffer enable delay, slow slew rate = off $V_{CCIO} = 2.5 \text{ V}$	C1 = 35 pF (5)		4.5		4.5		5.5	ns
t <sub>ZX3</sub>	Output buffer enable delay, slow slew rate = on V <sub>CCIO</sub> = 3.3 V	C1 = 35 pF		9.0		9.0		10.0	ns
$t_{XZ}$	Output buffer disable delay	C1 = 5 pF		4.0		4.0		5.0	ns
t <sub>SU</sub>	Register setup time		1.3		2.0		2.9		ns
t <sub>H</sub>	Register hold time		0.6		1.0		1.3		ns
t <sub>FSU</sub>	Register setup time of fast input		1.0		1.5		1.5		ns
t <sub>FH</sub>	Register hold time of fast input		1.5		1.5		1.5		ns
$t_{RD}$	Register delay			0.7		1.2		1.6	ns
t <sub>COMB</sub>	Combinatorial delay			0.6		0.9		1.3	ns
t <sub>IC</sub>	Array clock delay			1.2		1.9		2.5	ns

Table 20	Table 20. EPM7064AE Internal Timing Parameters (Part 2 of 2)   Note (1)											
Symbol	Parameter	Conditions	Speed Grade									
			-4		-7		-10					
			Min	Max	Min	Max	Min	Max				
$t_{EN}$	Register enable time			0.6		1.0		1.2	ns			
$t_{GLOB}$	Global control delay			1.0		1.5		2.2	ns			
t <sub>PRE</sub>	Register preset time			1.3		2.1		2.9	ns			
t <sub>CLR</sub>	Register clear time			1.3		2.1		2.9	ns			
$t_{PIA}$	PIA delay	(2)		1.0		1.7		2.3	ns			
$t_{LPA}$	Low-power adder	(6)		3.5		4.0		5.0	ns			

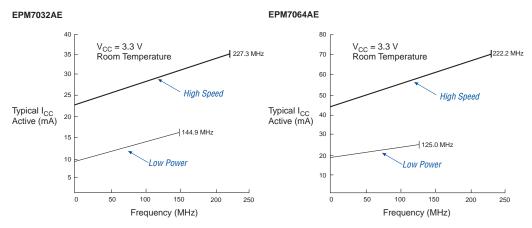
Symbol	Parameter	Conditions	Speed Grade						
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t <sub>EN</sub>	Register enable time			0.7		1.0		1.3	ns
$t_{GLOB}$	Global control delay			1.1		1.6		2.0	ns
t <sub>PRE</sub>	Register preset time			1.4		2.0		2.7	ns
t <sub>CLR</sub>	Register clear time			1.4		2.0		2.7	ns
$t_{PIA}$	PIA delay	(2)		1.4		2.0		2.6	ns
$t_{LPA}$	Low-power adder	(6)		4.0		4.0		5.0	ns

Symbol	Parameter	Conditions				Speed	Grade				Unit
			-6		-7		-10		-12		
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		6.0		7.5		10.0		12.0	ns
t <sub>PD2</sub>	I/O input to non- registered output	C1 = 35 pF (2)		6.0		7.5		10.0		12.0	ns
t <sub>SU</sub>	Global clock setup time	(2)	4.2		5.3		7.0		8.5		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		2.5		3.0		3.0		3.0		ns
t <sub>FH</sub>	Global clock hold time of fast input		0.0		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.7	1.0	4.6	1.0	6.1	1.0	7.3	ns
t <sub>CH</sub>	Global clock high time		3.0		3.0		4.0		5.0		ns
t <sub>CL</sub>	Global clock low time		3.0		3.0		4.0		5.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.9		2.4		3.1		3.8		ns
t <sub>AH</sub>	Array clock hold time	(2)	1.5		2.2		3.3		4.3		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	6.0	1.0	7.5	1.0	10.0	1.0	12.0	ns
t <sub>ACH</sub>	Array clock high time		3.0		3.0		4.0		5.0		ns
t <sub>ACL</sub>	Array clock low time		3.0		3.0		4.0		5.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset	(3)	3.0		3.0		4.0		5.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		6.9		8.6		11.5		13.8	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (4)	144.9		116.3		87.0		72.5		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		6.9		8.6		11.5		13.8	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (4)	144.9		116.3		87		72.5		MHz

Symbol	Parameter	Conditions	Speed Grade								
			-6		-7		-10		-12		
			Min	Max	Min	Max	Min	Max	Min	Max	
t <sub>RD</sub>	Register delay			1.7		2.1		2.8		3.3	ns
t <sub>COMB</sub>	Combinatorial delay			1.7		2.1		2.8		3.3	ns
t <sub>IC</sub>	Array clock delay			2.4		3.0		4.1		4.9	ns
t <sub>EN</sub>	Register enable time			2.4		3.0		4.1		4.9	ns
t <sub>GLOB</sub>	Global control delay			1.0		1.2		1.7		2.0	ns
t <sub>PRE</sub>	Register preset time			3.1		3.9		5.2		6.2	ns
t <sub>CLR</sub>	Register clear time			3.1		3.9		5.2		6.2	ns
t <sub>PIA</sub>	PIA delay	(2)		0.9		1.1		1.5		1.8	ns
$t_{LPA}$	Low-power adder	(6)		11.0		10.0		10.0		10.0	ns

Figure 13 shows the typical supply current versus frequency for MAX 7000A devices.

Figure 13. I<sub>CC</sub> vs. Frequency for MAX 7000A Devices (Part 1 of 2)



### EPM7128A & EPM7128AE

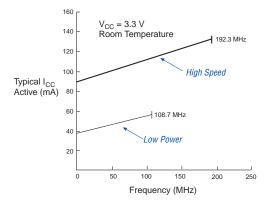
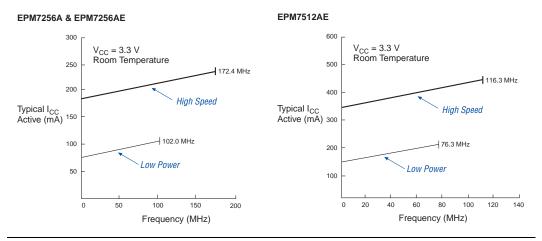


Figure 13. I<sub>CC</sub> vs. Frequency for MAX 7000A Devices (Part 2 of 2)



# Device Pin-Outs

See the Altera web site (http://www.altera.com) or the *Altera Digital Library* for pin-out information.

Figures 14 through 23 show the package pin-out diagrams for MAX 7000A devices.

Figure 14. 44-Pin PLCC/TQFP Package Pin-Out Diagram

Package outlines not drawn to scale.

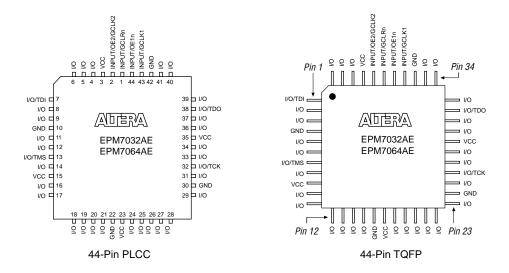


Figure 17. 100-Pin TQFP Package Pin-Out Diagram

Package outline not drawn to scale.

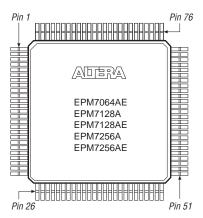


Figure 18. 100-Pin FineLine BGA Package Pin-Out Diagram

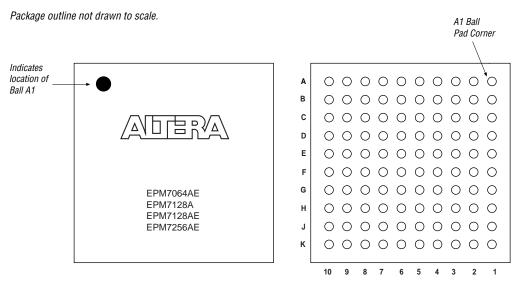


Figure 21. 208-Pin PQFP Package Pin-Out Diagram

Package outline not drawn to scale.

